

The Non-Invasive Attack Testing Workshop (NIAT 2011)

September 25-27, 2011

Nara Hotel (Reception)

Todai-ji Cultural Center (Technical Programs)

Nara, JAPAN

Organized by:

Cryptographic Module Validation Program (CMVP)

National Institute of Advanced Industrial Science and Technology (AIST)

Sponsored by:

Cryptography Research

Riscure

Day 0 (Nara Hotel) Sunday, September 25, 2011	
17:30	Registration
18:00 – 20:00 (2 hours)	Reception

Day 1 (Todai-ji Cultural Center) Monday, September 26, 2011	
9:00	Registration
9:30-10:30 (60 minutes)	Introduction
9:30	<ul style="list-style-type: none">• Opening Remarks <i>Randall Easter, CMVP NIST</i>
9:40	<ul style="list-style-type: none">• Workshop Overview <i>Akashi Satoh, AIST</i>
9:50	<ul style="list-style-type: none">• CMVP and FIPS Development <i>Randall Easter, CMVP NIST</i>
10:30-11:10 (40 minutes)	Break / Vendor Demo

11:10-12:20 (70 minutes)	<p style="text-align: center;">Technical Session 1 - Attack Methods 1 –</p> <p style="text-align: center;"><i>Session Chair: Hirofumi Sakane</i></p>
11:10	<ul style="list-style-type: none"> • Novel Applications of Wavelet Transforms based Side-Channel Analysis <i>Youssef Souissi¹, M.Aziz el Aabid^{1,2}, Jean-Luc Danger^{1,3}, Sylvain Guilley^{1,3}, Nicolas Debande^{1,4}</i> ¹ Telecom Paris-Tech, ² Université Paris 8, ³ Secure-IC SAS, ⁴ Morpho
11:45	<ul style="list-style-type: none"> • An Equidistant Message Power Attack Using Restricted Number of Traces on Reduction Algorithm <i>Jong-Yeon Park¹, Dong-Guk Han¹, Okyeon Yi¹, and Dooho Choi²</i> ¹ Cryptography and Information Security Institute(CISI), Department of Mathematics Kookmin University ² Electronic and Telecommunication Research Institute(ETRI)
12:20-14:00 (1 hour 40 minutes)	Lunch (Yumekaze Hiroba)
14:00-15:10 (70 minutes)	<p style="text-align: center;">Technical Session 2 - Attack Methods 2-</p> <p style="text-align: center;"><i>Session Chair: Caroline Scace</i></p>
14:00	<ul style="list-style-type: none"> • Practical Electro-Magnetic Analysis <i>Fred de Beer, Marc Witteman, and Bartek Gedrojc</i> Riscure
14:35	<ul style="list-style-type: none"> • Non-invasive Trigger-free Fault Injection Method Based on Intentional Electromagnetic Interference <i>Yu-ichi Hayashi, Naofumi Homma, Takeshi Sugawara, Takaaki Mizuki, Takafumi Aoki, and Hideaki Sone</i> Tohoku University
15:10-15:50 (40 minutes)	Break / Vendor Demo
15:50-17:00 (70 minutes)	<p style="text-align: center;">Technical Session 3 - Attack Methods 3 and Countermeasures –</p> <p style="text-align: center;"><i>Session Chair: Kim Schaffer</i></p>
15:50	<ul style="list-style-type: none"> • Choosing Distinguishers for Differential Power Analysis Attacks <i>Elisabeth Oswald, Luke Mather, and Carolyn Whitnall</i> University of Bristol, Department of Computer Science
16:25	<ul style="list-style-type: none"> • Efficient FPGA Implementation of dual-rail countermeasures using Stochastic Models <i>Shivam Bhasin, Sylvain Guilley, Youssef Souissi, Jean-Luc Danger</i> Telecom Paris-Tech
17:00	END of Day 1

Day 2 (Todai-ji Cultural Center) Tuesday, September 27, 2011	
8:30	Registration
9:00-10:00 (60 minutes)	DPA Contest Session <i>Session Chair: Caroline Scace</i>
	<ul style="list-style-type: none"> • Education and open benchmarking on side-channel analysis with the DPA contests <i>Jean-Luc Danger, Guillaume Duc, Sylvain Guilley and Laurent Sauvage</i> DPA Contest • Round table discussion <i>Moderator: Sylvain Guilley</i>
10:00-10:30 (30 minutes)	Break / Vendor Demo
10:30-12:00 (90 minutes)	Technical Session 4 - Test Methods and Metrics – <i>Session Chair: Hirofumi Sakane</i>
10:30	<ul style="list-style-type: none"> • A testing methodology for side-channel resistance validation <i>Gilbert Goodwill, Benjamin Jun, Josh Jaffe, and Pankaj Rohatgi</i> Cryptography Research Inc.
11:05	<ul style="list-style-type: none"> • Efficient side-channel testing for public key algorithms: RSA case study <i>Josh Jaffe¹, Pankaj Rohatgi¹, and Marc Witteman²</i> ¹ Cryptography Research Inc. ² Riscure
11:40	<ul style="list-style-type: none"> • Extended discussion
12:00-13:40 (1 hour 40 minutes)	Lunch (Yumekaze Hiroba)
13:40-14:40 (60 minutes)	Panel Discussion – Tool Vendor / Laboratory – <i>Theme: Test Automation and Metrics</i> <i>Moderator: Randall Easter</i> <i>Panelists : BrightSight, Cryptography Research, Riscure, Secure-IC</i>
14:40-15:10 (30 minutes)	Break / Vendor Demo
15:10-17:15 (125 minutes)	Technical Session 5 - Test Tools and Methods – <i>Session Chair: Kim Schaffer</i>

15:10	<ul style="list-style-type: none"> • Side-Channel Attack Standard Evaluation Board SASEBOW for Smartcard Testing <i>Toshihiro Katashita, Yohei Hori, Hirofumi Sakane, and Akashi Satoh</i> National Institute of Advanced Industrial Science and Technology (AIST)
15:45	<ul style="list-style-type: none"> • Test Apparatus for Side-Channel Resistance Compliance Testing <i>Michael Hutter, Jörn-Marc Schmidt, Thomas Plos, and Mario Kirschbaum</i> Institute for Applied Information Processing and Communications (IAIK), Graz University of Technology
16:20	<ul style="list-style-type: none"> • Evaluation Tools for Side-Channel Attacks: An Overview <i>François-Xavier Standaert</i> UCL Crypto Group, Université catholique de Louvain
16:55	<ul style="list-style-type: none"> • Extended discussion
17:15-17:25	<p style="text-align: center;">Concluding Remarks</p> <p style="text-align: center;"><i>Randall Easter, CMVP NIST</i></p>
17:25	END of Day 2

Technical session presentation : 35 minutes per presenter. (25-minute presentation including introduction followed by 10-minute discussion)

Updated: 09/22/2011